



# Peifang Tian, Ph.D.

ATTORNEY

Peifang has extensive experience in drafting and prosecuting domestic and foreign patents.



## Practices

[Complex Litigation](#)  
[Patent Litigation](#)  
[Patent](#)

## Languages

Chinese

## Education

Columbus School of Law at The Catholic University of America, JD, 2024  
Princeton University, PhD, 2003  
Tsinghua University, MS, 1995  
Tsinghua University, BS, 1993

## Offices

[Washington, DC](#)

## Phone

[202.350.3073](#)

## Email

[Peifang.Tian@afslaw.com](mailto:Peifang.Tian@afslaw.com)

Peifang brings to the firm a variety of technical expertise in electrical engineering, physics, and neurosciences; more specifically she offers extensive research experiences in semiconductor processing and devices, optical systems, ultrafast laser spectroscopy, and biomedical imaging. She drafts and prosecutes patent applications for domestic and foreign companies in a wide array of technologies including video coding, telecommunications, quantum computing, semiconductor processing and devices, artificial intelligence, blockchain, video games, computer software, automotive related technologies, medical devices, and consumer electronics.

## Previous Work

Prior to joining ArentFox Schiff, Peifang worked as a Patent Agent/Technical Advisor at an intellectual property law firm in Northern Virginia. She drafted and prosecuted patent applications for domestic and foreign companies for complex technologies.

Prior to her legal career, she conducted research and taught in academia for twelve years, first at the University of California, San Diego as an Assistant Project Scientist and then at John Carroll University as an Assistant and Associate Professor. She conducted research as an optical engineer/physicist at the Global Research Center of General Electric.

Peifang holds US, European, and German patent(s) for her work on OLEDs and holographic data storage and has more than twenty peer-reviewed publications including a paper in *Science* on ultrafast laser spectroscopy.

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## Court Admissions

[US Patent and Trademark Office](#)